

Search Notes



Application/Control No.

10/517,066

Examiner

Sang Y. Paik

Applicant(s)/Patent under
Reexamination

SATOU ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
219	450.1 452.11 452.12		
	457.1 460.1		
	455.11		
26	21R 21A		
	299R 299D		
	299E		
99	422 423		
	422 444		
	445		
411	203 204		
	205 206		
	207 212.1	7/21/05	SP

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST ASIAN CORP	7/21/05	SP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Art 600C		7/21/05	SP